

### **Features**

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q,,)
- Halogen free, RoHS compliant

### **Benefits**

- · Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

## **Applications**

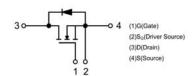
- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies





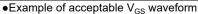
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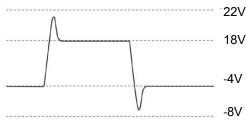
SOT-227



# **Maximum Ratings** (T<sub>c</sub> = 25 °C unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-source voltage	$V_{DS}$	1200	V
Continuous drain current $T_C = 25^{\circ}C$ , $V_{GS} = 18V$ $T_C = 100^{\circ}C$ , $V_{GS} = 18V$	I <sub>D</sub>	125 90	А
Pulsed drain current ( $T_C = 25^{\circ}C$ , $t_p$ limited by $T_{jmax}$ )	I <sub>D pulse</sub>	250	Α
Gate-Source voltage	V <sub>GS</sub>	-4/+18	V
Gate-Source voltage(Absolute maximum values)	$V_{GSmax}$	-8/+22	V
Power dissipation (T <sub>C</sub> = 25°C)	P <sub>tot</sub>	681	W
Operating junction and storage temperature	$T_j$ , $T_stg$	-40+175	°C







## **Thermal Resistance**

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case. Max	$R_{thJC}$	0.22	°C/W

# Electrical Characteristic (at Tj = 25 °C, unless otherwise specified)

Poromotor	Cumbal	Value			l lmi4	Test Condition
Parameter	Symbol	min.	typ.	max.	Unit	Test Condition
Static Characteristic						
Drain-source breakdown voltage	BV <sub>DSS</sub>	1200	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA
Gate threshold voltage	V <sub>GS(th)</sub>	2	3	4	V	$V_{DS}=V_{GS}$ , $I_{D}=25$ mA
						V <sub>DS</sub> =1200V,V <sub>GS</sub> =0
Zero gate voltage drain current	I <sub>DSS</sub>	-	1	50	μΑ	V T <sub>C</sub> =25°C
		-	10	-		T <sub>C</sub> =175°C
Gate-source leakage current	I <sub>GSS</sub>	-		200	nA	V <sub>GS</sub> =18V,V <sub>DS</sub> =0V
						V <sub>GS</sub> =18V,
Drain-source on-state	R <sub>DS(on)</sub>	-	15	22	mΩ	I <sub>D</sub> =80A, T <sub>J</sub> =25°C
resistance		-	29	-		T <sub>J</sub> =175°C
Transconductance	g <sub>fs</sub>	-	43	-	S	V <sub>DS</sub> =20V,I <sub>D</sub> =40A



# **Dynamic Characteristic**

Input Capacitance	C <sub>iss</sub>	-	4508	-		$V_{DS} = 1000V$ $V_{GS} = 0V$
Output Capacitance	C <sub>oss</sub>	-	214	ı	pF	$T_J = 25^{\circ}C$
Reverse Transfer Capacitance	C <sub>rss</sub>	-	26	ı	nC	$V_{AC} = 25 \text{mV}$ $f = 1 \text{MHz}$ $V_{DS} = 800 \text{V}$ $V_{GS} = 0/18 \text{V}$
Gate Total Charge	$Q_G$	-	222	ı		
Gate-Source charge	$Q_{gs}$	-	46.4	-		
Gate-Drain charge	$Q_{gd}$	-	77.6	-	mJ ns	$I_D = 80A$ $V_{DD} = 800V$ $V_{GS} = -4/+18V$ $I_D = 80A$ $R_G = 5\Omega$ $L = 120uH$
Turn-On Switching Energy	E <sub>ON</sub>	-	2.29	1		
Turn-Off Switching Energy	E <sub>OFF</sub>	-	0.63	ı		
Turn-on delay time	t <sub>d(on)</sub>	-	49.2	ı		
Rise time	t <sub>r</sub>	-	14.2	ı		
Turn-off delay time	t <sub>d(off)</sub>	-	21.7	1		
Fall time	t <sub>f</sub>	-	11.3	-		
Gate resistance	$R_G$	-	0.9	-	Ω	$V_{AC} = 25 \text{mV}, f=1 \text{MHz}$

# **Body Diode Characteristic**

	Symbol	Value				T 10 III
Parameter		min.	typ.	max.	Unit	Test Condition
Pady Diada Farward Valtage	ody Diode Forward Voltage  V <sub>SD</sub> 4.4  3.9		V	$V_{GS}$ =-4V, $I_{SD}$ =40A, $T_{J}$ =25°C		
Body Diode Forward Voltage			3.9		V	V <sub>GS</sub> =-4V,I <sub>SD</sub> =40A, T <sub>J</sub> =175°C
Body Diode Reverse Recovery Time	t <sub>rr</sub>	-	29.6	-	ns	V <sub>R</sub> = 800V I <sub>D</sub> = 80A
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	-	272	-	nC	di/dt = 1000A/μS Τ <sub>J</sub> = 25°C



# **Typical Performance Characteristics**

Fig 1. Output Characteristic (T<sub>j</sub>=-55°C)

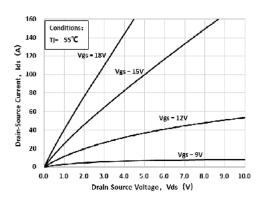


Fig 3. Output Characteristic (T<sub>J</sub>=175℃)

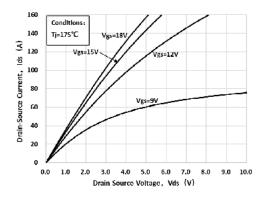


Fig 5: Rds(on) vs. Temperature

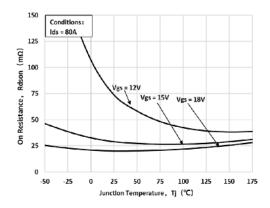


Fig 2. Output Characteristic (T<sub>J</sub>=25℃)

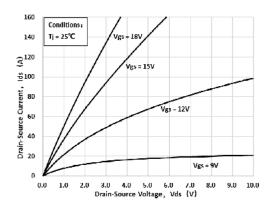


Fig 4: Rdson Vs Ids Characteristic

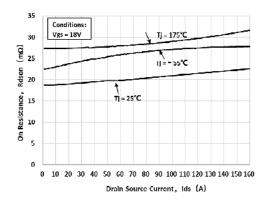


Fig 6: Transfer Characteristic

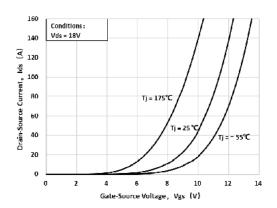




Fig 7: Body-diode Characteristic (T<sub>J</sub>=-55°C)

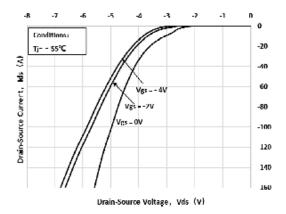


Fig 9: Body-diode Characteristic (T<sub>J</sub>=175℃)

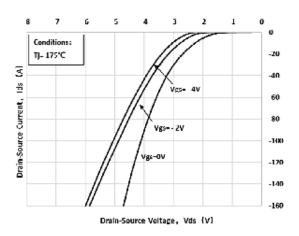


Fig 11: Gate Charge Characteristics

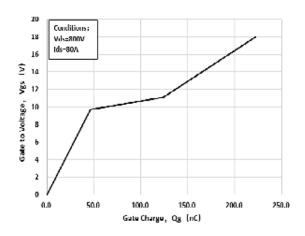


Fig 8: Body-diode Characteristic (T<sub>J</sub>=25℃)

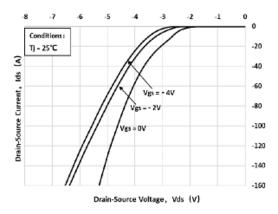


Fig 10: V<sub>TH</sub> Vs T<sub>J</sub> Temperature Characteristic

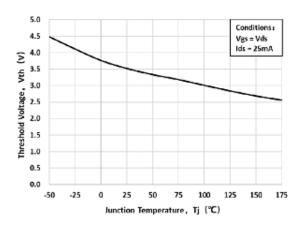


Fig 12: 3rd Quadrant Characteristic(T<sub>J</sub>=-55°C

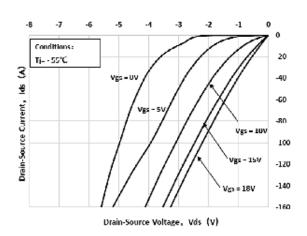




Fig 13: 3rd Quadrant Characteristic(T<sub>J</sub>=25℃)

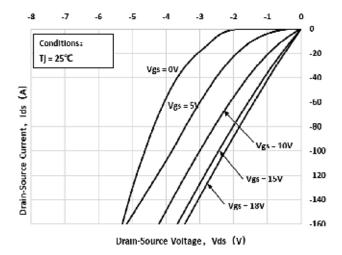


Fig 15: Capacitance Characteristic

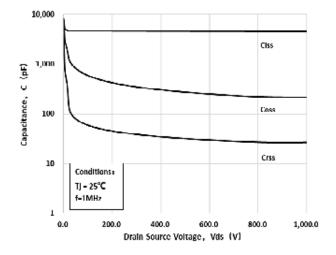


Fig 14: 3rd Quadrant Characteristic(T<sub>J</sub>=175℃)

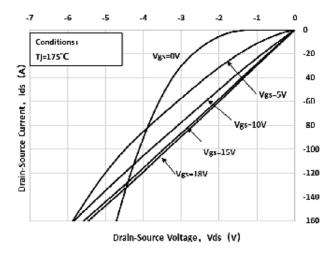
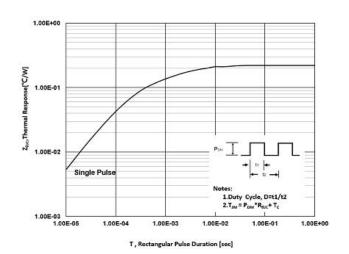


Fig 17: Transient Thermal Impedance





# **Test Circuit & Waveform**

Figure A. Definition of switching times

Figure B. Dynamic test circuit

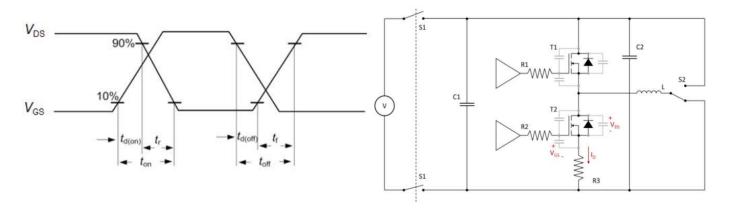


Figure C. Definition of body diodeswitching characteristics

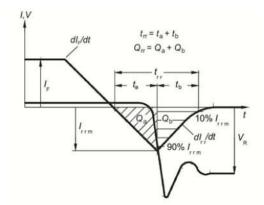
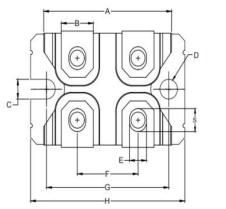


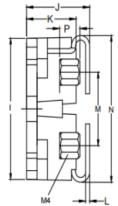
Figure C. Definition of diode switching characteristics

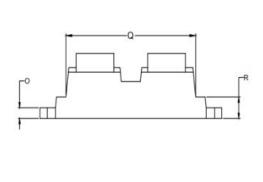


# Package Dimensions

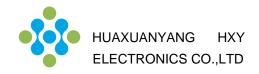
Package SOT-227







DiM	Millimeter				
DiM	Min	Max			
Α	31.40	31.60			
A B	7.70	8.10			
С	4.20	4.40			
D E F	4.20	4.40			
E	4.10	4.30			
	14.90	15.10			
G	30.10	30.20			
Н	38.00	38.40			
	23.80	24.20			
J	12.20	12.70			
K	9.40	9.60			
L	0.75	0.85			
M	12.40	12.80			
N	24.50	25.40			
O P	1.90	2.10			
	3.10	3.95			
Q R	26.60	27.00			
R	3.80	4.20			
S	5.10	5.40			



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